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Cypher ES Environmental AFM



The Asylum Research **Cypher ES** builds on the exceptional performance of the Cypher S and adds full environmental control features. The same high resolution, speed and stability are maintained while easily operating in controlled gas or liquid environments, at temperatures from 0-250°C, and in some of the harshest chemical environments. The Cypher ES is the ultimate AFM for the most demanding experimental requirements.

- Routinely achieve higher resolution than other AFMs
- Fast scanning with results in seconds instead of minutes
- Every step of operation is simpler for remarkable productivity
- Small footprint in the lab, huge potential to grow in capability
- Support that goes above and beyond your expectations
- Enables gas and liquid perfusion through a sealed cell
- Controls sample temperature over a wide 0-250°C range
- Broadest compatibility with harsh chemicals

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Features and Benefits

Operating Modes

Accessories

Software

Support

Included Operating Modes

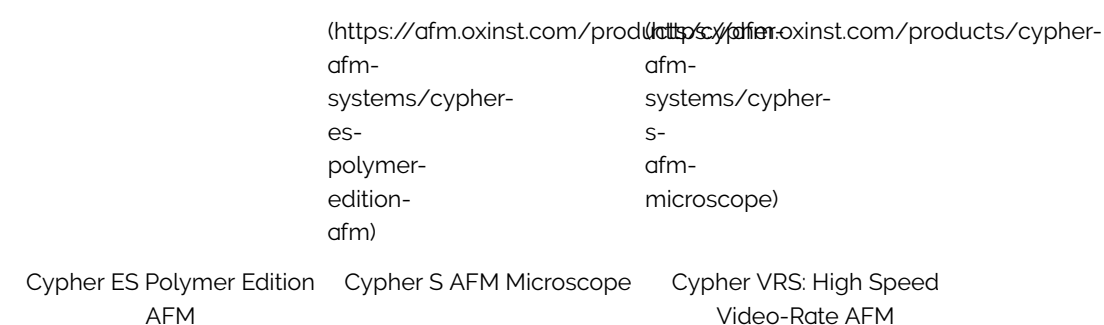
Contact mode
 DART PFM
 Dual AC
 Dual AC Resonance Tracking (DART)
 Electrostatic Force Microscopy (EFM)
 Force curves
 Force Mapping Mode (force volume)
 Force modulation
 Frequency modulation
 Kelvin Probe Force Microscopy (KPFM)
 Lateral Force Mode (LFM)
 Loss tangent imaging
 Magnetic Force Microscopy (MFM)
 Nanolithography
 Nanomanipulation
 Phase imaging
 Piezoresponse Force Microscopy (PFM)
 Switching spectroscopy PFM
 Tapping mode (AC mode)
 Tapping mode with digital Q control
 Vector PFM

Optional Operating Modes

AM-FM Viscoelastic Mapping Mode
 Contact Resonance Viscoelastic Mapping Mode
 Conductive AFM (CAFM) with ORCA™ and Eclipse™ Mode
 Current mapping with Fast Force Mapping
 Electrochemical Strain Microscopy (ESM)
 Fast Force Mapping Mode
 High voltage PFM
 Nanoscale Time Dependent Dielectric Breakdown (nanoTDDB)
 Scanning Microwave Impedance Microscopy (sMIM)
 Scanning Tunneling Microscopy (STM)

Note: Some optional modes on the Cypher ES require blueDrive photothermal excitation. sMIM requires the Cypher S scanner.

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